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Ptical Property Measurements as Control of Materials Processing a Diagnostic in Space and Tool for on Earth

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ABSTRACT

quiescent melts enablir interesting phenomenon ollowing, fully method, including essing in 9 melts enabling undercooling, glass ng phenomenon to occur readily. Ho , controlling developed at via o f new materials the and major exciting materials liquid state. The results, to measure, SC and measuring processing parameters this time. In this paper, we descr in microgravity ienc O justifications The lack of convection produc this paper, through high temperature However, methods control and formation and for describe and follow are or ч æ

emittance decreases very rapidly with increasing temperature. Consequently, the processing of materials at high temperature can be controlled quite well through the control of surface Experiments on aluminum show the disappearnce of the oxide (emittance 0.33) at ca. 1300 C leaving a liquid surface with an emittance of 0.06. Electromagnetic levitation of silicon shows liquid with a constant emittance (0.2) but with a solid whose emittance decreases very rapidly with increasing temperature. aluminum, succesfully containerless processing in ground based levitators. This new technique enables instantaneous optical neasurements from a transient solid or liquid surface with true temperature measurement. This has been used successfully as a diagnostic tool to follow processing ptical ience properties. Candidate materials justifications will be presented. properties. ly as a diagnostic tool to rottow processilicon and titanium during electromagnetic will be described used o f property concurrent levitation.

levitation experiments for dependence olarimetry ontainerless sics liqterature. the LTS: The first figure illustrates the change occurs on reflection from a surface and also polarimeter summarizes the the i n laser the 1. S ser polarimetric technique as a diagnostic ss processing. The third figure shows the to of the spectral emissivity for clean liquid fourth sensitive case The in the case slide of iridium last experiments to changes in compares the data obtained in solid and liquid silicon with thos figure shows oxide formation and of illustrating that anges in surface c surface and also the a levitated droplet. s that illustrate the diagnostic chemistry laser in polarizat the design o design of The secon versatility temperature aluminum tool and second ion

CONCLUSION: It has been clearly polarimetry is a fast, reproduc Polarimetric Pyrometer (DAPP) ntersonics is hemistry and physics measurement. currently to developing be monitored and controlled. for ible t demonstrated that accurate the echnique Division temperature that allows of Amplitud laser and pro C

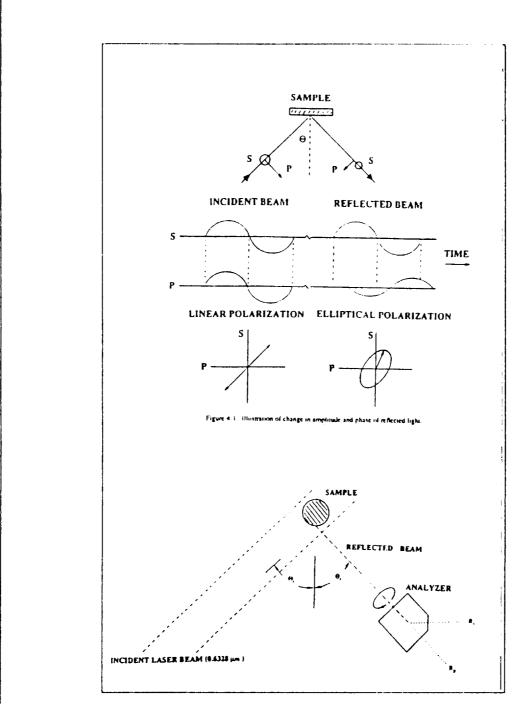


Illustration of Rotating Analyzer Ellipsometry

SUMMARY

MATERIALS AT HIGH TEMPERATURES IN CONTAINERLESS LASER POLARIMETRY IS FAST, REPRODUCIBLE, AND Exact method to measure the optical properties EXPERIMENTS.

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IT HAS BEEN USED TO FOLLOW: -}{-

OXIDATION - Ir, B

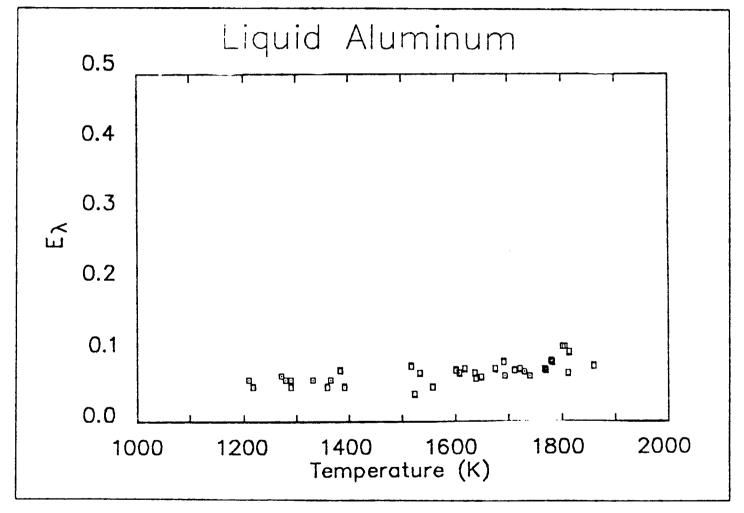
PHASE TRANSFORMATION - Hf

MELTING, UNDERCOOLING — Nb, Pt, Pd, Si Band Structure changes — Cu, Au, Pd

IS BEING DEVELOPED FOR MICROGRAVITY APPLICATIONS BY DIVISION OF AMPLITUDE POLARIMETRIC PYRAMETER (DAPP) INTERSONICS INCORPORATED.

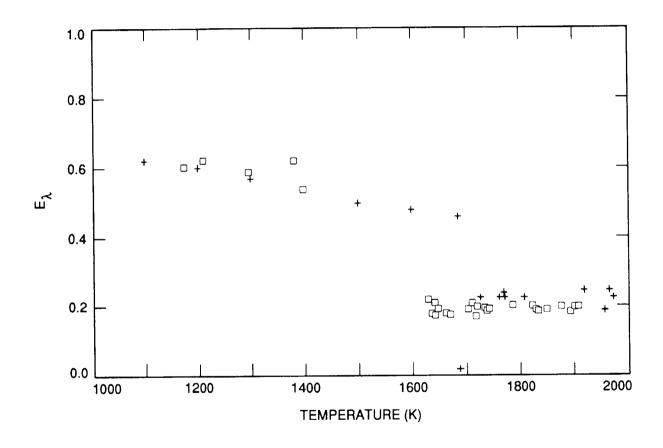
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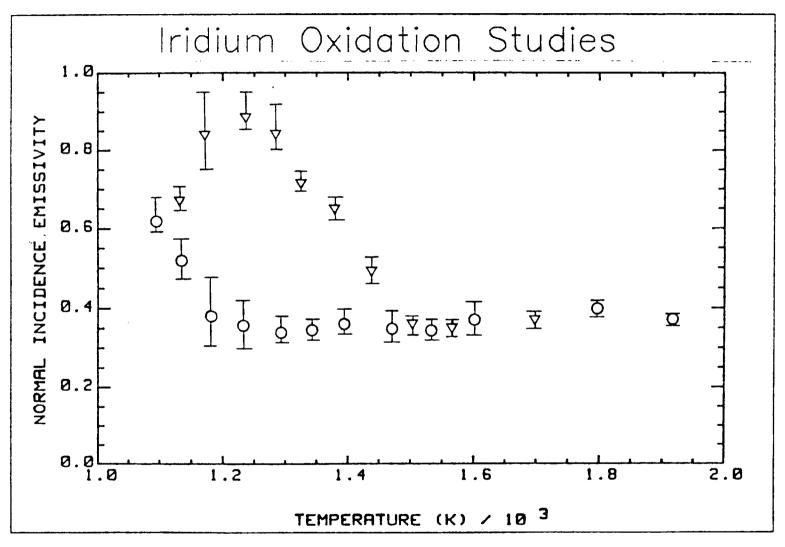


Normal incidence spectral emissivity of liquid aluminum as a function of temperature at 633 nm (\Box) .

SOLID AND LIQUID SILICON



NORMAL INCIDENCE SPECTRAL EMISSIVITY OF SOLID AND LIQUID SILICON AS A FUNCTION OF TEMPERATURE AT 633 nm (\Box). LITERATURE DATA INDICATED BY (+). MELTING POINT INDICATED BY ARROW.



Oxidation hystersis of iridium reprsenting the average results of experiments in air, 10% O_2 — Ar, and 30% O_2 — Ar taken during a cooling (O) and heating (∇) cycle.